Notice of References Cited	Application/Control No. 10/677,305	Applicant(s)/Patent Under Reexamination YOON ET AL.	
	Examiner B. Clayton McCraw	Art Unit 3744	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0069652	06-2002	Roh et al.	62/126
*	B	US-6,622,925	09-2003	Carner et al.	236/46R
*	C	US-6,736,328	05-2004	Takusagawa, Masaru	236/51
*	D	US-2003/0070438	04-2003	Kikuchi et al.	62/141
*	E	US-2001/0003906	06-2001	Roh, Young Hoon	62/231
*	F	US-2003/0019944	01-2003	Nonaka et al.	236/51
*	G	US-6,789,739	09-2004	Rosen, Howard	236/51
*	H	US-2003/0140637	07-2003	Masui et al.	62/127
*	I	US-2003/0055534	03-2003	Saito et al.	700/276
*	J	US-5,104,037	04-1992	Karg et al.	236/46R
*	K	US-2002/0014538	02-2002	Weimer et al.	236/51
*	L	US-6,625,996	09-2003	Nakajima et al.	62/175
*	M	US-6,874,691	04-2005	Hildebrand et al.	236/51

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.